



Appendix C Summary of Commercial Reliability Programs

P+ Product Enhancement

The P+ product enhancement program involves dynamic tests that screen out assembly related and silicon defects that can lead to infant mortality and/or reduce the survival

ability of the device under high stress conditions. This program includes but is not limited to the following power devices:

Device	Package Types					
	TO-3 K STEEL	TO-39 (H)	TO-220 (T)	DIP (N)	SO (M)	TO-263 (S)
LM12	X					
LM109/309	X	X				
LM117/317	X	X	X			X
LM117HV/317HV	X	X				
LM120/320	X	X	X			
LM123/323	X					
LM133/333	X		X			
LM137/337	X	X	X			
LM137HV/337HV	X	X				
LM138/338	X		X			
LM140/340	X		X			
LM145/345	X					
LM150/350	X		X			
LM195/395	X	X	X			
LM2930/2935/2984			X			X
LM2937			X			X
LM2940/2941			X			X
LM2990/2991			X			X
LM2575/2575HV			X	X	X	X
LM2576			X			X
LM2577			X	X	X	X
LMD18200/18201			X			